

# NEOSEM

## Supported Protocols

- PCIe 2.0, PCIe 3.0
- SATA 3/6 Gbps
- SAS 3/6/12 Gbps
- AHCI, NVMe

## Supported Form Factors

- Edge Card (AIC)  
FHHL, HHHL
- 1.8", 2.5", 3.5"
- U.2
- mSATA
- M.2

## System Scalability

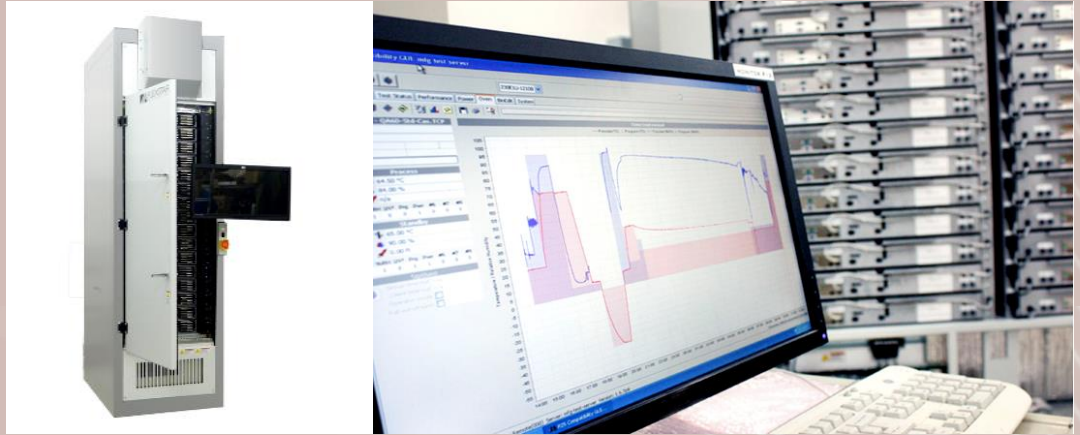
- **F-8A (Ambient)**  
Bench-top Tester  
Up to 4 Parallel DUTs
- **F-60B (+10C to +85C)**  
1-zone Chamber  
Up to 120 Parallel DUTs(AIC)  
Up to 240 Parallel DUTs(M.2)
- **F-60E (-34C to +85C)**  
1-zone Chamber  
Up to 192 Parallel DUTs(AIC)  
Up to 192 Parallel DUTs(M.2)

**NEOSEM**  
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# F-60B SSD Test System



## F-60B Burn-In SSD, HDD Chamber Test System

The F-60B Burn-in test system is based on a high-density, small footprint that can be connected to create larger test capacities. The F-60B not only tests devices as generic drives, but also probes the unique failure modes and attributes of the underlying technology. The system utilizes Neosem's robust Andromeda operating software platform with a comprehensive library of standard tests. Our software also allows user-defined and user-developed test scripts through the provided test development platform.

## Key Features

- Small footprint (19" rack-based)
- Tailored to SSD or PCIe Testing with SAS, SATA, AHCI, NVMe plus Backdoor Serial interfaces
- Programmable power margining per DUT with current and voltage measurement read-back
- Turnkey solution, featuring Neosem's Andromeda operating software
- User-friendly GUI allows for easy test control (start/stop) and monitoring (status) of all Device Under Test (DUT) on one screen
- Provides characterization data such as performance, measurement, throughput, IOPs, thermal and power consumption
- GUI allows intuitive drill down monitoring from scripts level through DUT interface commands and down to bit level write and operations
- Comprehensive library of engineering, reliability, quality and production test scripts designed for HDD, SSD and PCIe devices

# F-60B SSD Test System

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## Product Specifications

### Mechanical

- Exterior Dimensions: 24" wide x 98" tall x 47" deep

### Input Power

- 208, 230 Volts 3 Phase(Optional international voltage available)

### Software

- Test results are delivered in clear, detailed reports and graphs
- Test script development tools
- GUI driven test control platform
- Debug through interactive shell command interface
- Individually captured information for every DUT
- Run multiple tests, simultaneously
- API for user-defined plug-ins
- Script/Java Support
- SNIA and JEDEC Compliance Test



### Applications

- Production Testing (Factory)
- Qualification & Device Screening
- Quality Assurance
  - Reliability Demonstration Testing (RDT)
  - Ongoing Reliability Testing (ORT)
  - Design Verification Testing (DVT)

## Supported Protocols

- HDD 2.5" , 3.5"
- PCIe 2.0, PCIe 3.0
- SATA 3/6 Gbps
- SAS 3/6/12 Gbps
- AHCI, NVMe

## Supported Form Factors

- Edge Card (AIC)  
FHHL, HHHL
- 1.8", 2.5", 3.5"
- U.2
- mSATA
- M.2

## System Scalability

- F-8A ( Ambient )**  
Bench-top Tester  
Up to 4 Parallel DUTs
- F-60B ( +10C to +85C )**  
1-zone Chamber  
Up to 120 Parallel DUTs(AIC)  
Up to 240 Parallel DUTs(M.2)
- F-60E ( -34 C to +85C )**  
1-zone Chamber  
Up to 192 Parallel DUTs(AIC)  
Up to 192 Parallel DUTs(M.2)

## F-60B Tester System Specifications

SSD ( 2.5" ) 208 DUTs

HDD ( 3.5" ) 64 DUTs

PCIe SSD 120 DUTs (AIC)  
240 DUTs (M.2)

Chamber Temperature Range Ambient :+10 to + 85 C

Test Application Development P25 Script & JAVA Support

Tester Input Power 220 or 380V AC – 50 to 60HZ 3 Phase

Tester Operating Temperature Range 18C to 28 Degree C – Air cooled

Tester Software Andromeda Operating S/W

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